



FQD3P50 / FQU3P50

500V P-Channel MOSFET

General Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

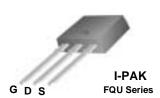
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for electronic lamp ballast based on complimentary half bridge.

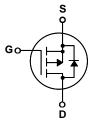
Features

- -2.1A, -500V, $R_{DS(on)} = 4.9\Omega @V_{GS} = -10 \text{ V}$
- Low gate charge (typical 18 nC)
- Low Crss (typical 9.5 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD3P50 / FQU3P50	Units
V _{DSS}	Drain-Source Voltage		-500	V
I _D	Drain Current - Continuous (T _C = 25°C)		-2.1	А
	- Continuous (T _C = 100	- Continuous (T _C = 100°C)		Α
I _{DM}	Drain Current - Pulsed	(Note 1)	-8.4	Α
V_{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	250	mJ
I _{AR}	Avalanche Current	(Note 1)	-2.1	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns
P _D	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		50	W
	- Derate above 25°C		0.4	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

* When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-500			V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = -250 μA, Referenced to 25°C		0.42		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -500 V, V _{GS} = 0 V		-	-1	μΑ
		V _{DS} = -400 V, T _C = 125°C			-10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V		-	-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V		-	100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0	I	-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -1.05 A		3.9	4.9	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = -50 \text{ V}, I_D = -1.05 \text{ A} \text{ (Note 4)}$		2.1		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		510 70	90	pF pF
C _{rss}	Reverse Transfer Capacitance			9.5	12	pF
t _{d(on)}	Turn-On Delay Time			12	35	ns
t _r	Turn-On Rise Time	$V_{DD} = -250 \text{ V}, I_{D} = -2.7 \text{ A},$		56	120	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$		35	80	ns
	Turn-Off Fall Time	(Note 4, 5)		45	100	ns
ι _f				18	23	nC
•	Total Gate Charge	$V_{DS} = -400 \text{ V. } I_{D} = -2.7 \text{ A.}$		10	20	
Q _g	Total Gate Charge Gate-Source Charge	$V_{DS} = -400 \text{ V}, I_{D} = -2.7 \text{ A},$ $V_{GS} = -10 \text{ V}$		3.6		nC
Q _g	· ·	7 50				
Q _g Q _{gs} Q _{gd}	Gate-Source Charge	V _{GS} = -10 V (Note 4, 5)		3.6		nC
Q _g Q _{gs} Q _{gd} Drain-S	Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and	V _{GS} = -10 V (Note 4, 5) nd Maximum Ratings ode Forward Current		3.6 9.2		nC nC
Q_g Q_{gs} Q_{gd} Drain-S	Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and Maximum Continuous Drain-Source Diode	V _{GS} = -10 V (Note 4, 5) nd Maximum Ratings ode Forward Current		3.6 9.2	-2.1	nC nC
Q _{gs} Q _{gd} Drain-S I _S	Gate-Source Charge Gate-Drain Charge Source Diode Characteristics as Maximum Continuous Drain-Source Diode Maximum Pulsed Drain-Source Diode F	v _{GS} = -10 V (Note 4, 5) nd Maximum Ratings ode Forward Current Forward Current		3.6 9.2	-2.1 -8.4	nC nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 102mH, I_{AS} = -2.1A, V_{DD} = -50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq -2.7A, dil/dt \leq 200A/μs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

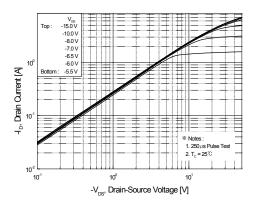


Figure 1. On-Region Characteristics

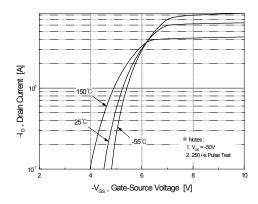


Figure 2. Transfer Characteristics

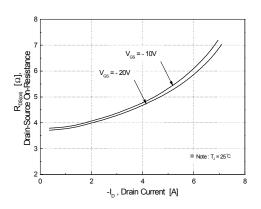


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

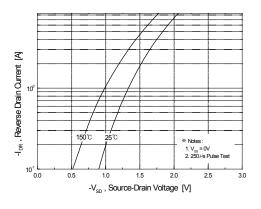


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

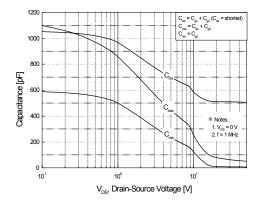


Figure 5. Capacitance Characteristics

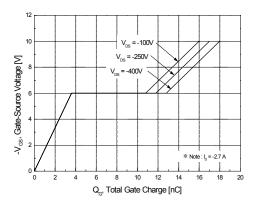
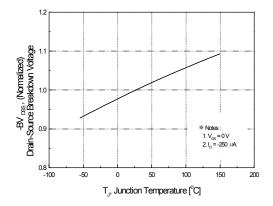


Figure 6. Gate Charge Characteristics

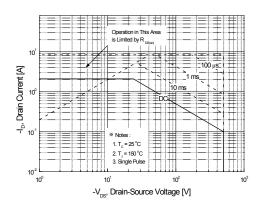




2.5 (Normalized) 1.5 (N

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



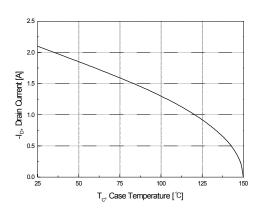


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

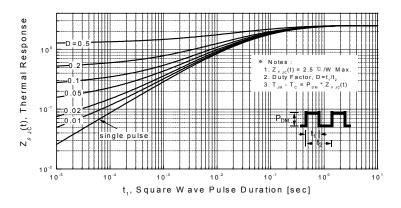
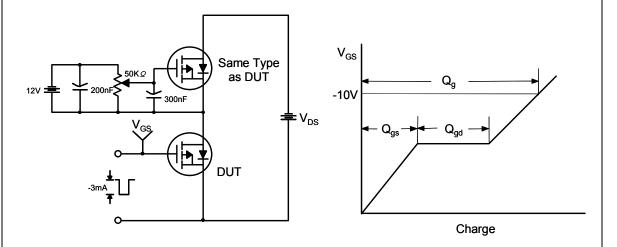


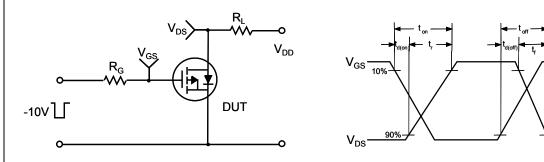
Figure 11. Transient Thermal Response Curve

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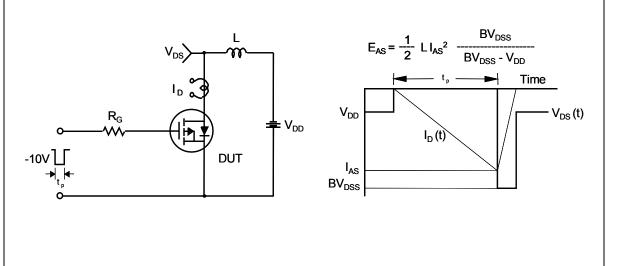
Gate Charge Test Circuit & Waveform



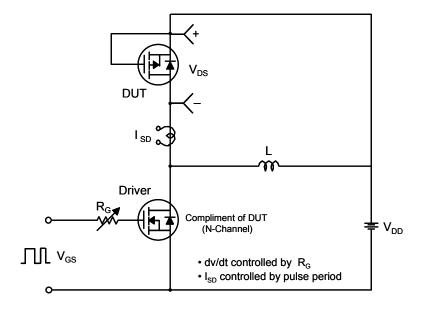
Resistive Switching Test Circuit & Waveforms

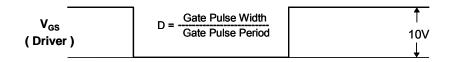


Unclamped Inductive Switching Test Circuit & Waveforms

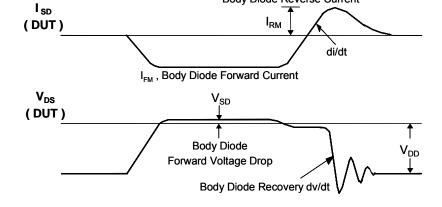


Peak Diode Recovery dv/dt Test Circuit & Waveforms





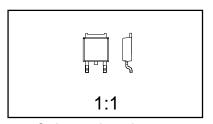
Body Diode Reverse Current



Mechanical Dimensions

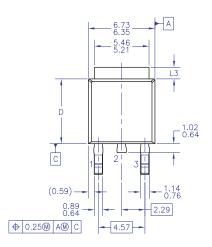
TO-252 (DPAK) (FS PKG Code 36)

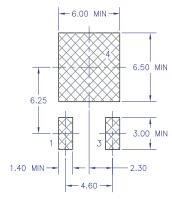




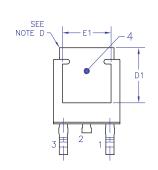
Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

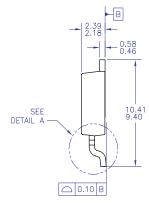
Part Weight per unit (gram): 0.33

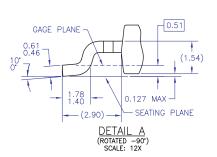




LAND PATTERN RECOMMENDATION







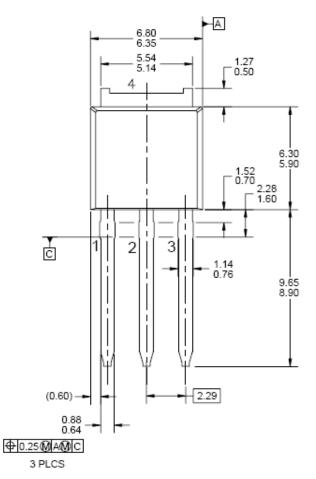
- NOTES: UNLESS OTHERWISE SPECIFIED

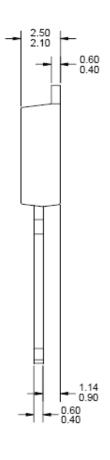
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 ISSUE C, VARIATION AA & AB, DATED NOV. 1999.
 DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M-1994.
 HEAT SINK TOP EDGE COULD BE IN CHAMFERED
 CORNERS OR EDGE PROTRUSION.
 DIMENSIONS L3,D,E1&D1 TABLE:

	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D1	5.21 MIN	4.57 MIN

Mechanical Dimensions

I - PAK







Dimensions in Millimeters





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